
**Surface chemical analysis — Auger
electron spectroscopy and X-ray
photoelectron spectroscopy —
Methods used to determine peak
intensities and information required
when reporting results**

*Analyse chimique des surfaces — Spectroscopie des électrons Auger
et spectroscopie de photoélectrons par rayons X — Méthodes utilisées
pour la détermination de l'intensité des pics et informations requises
pour l'expression des résultats*





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CP 401 • Ch. de Blandonnet 8
CH-1214 Vernier, Geneva
Phone: +41 22 749 01 11
Fax: +41 22 749 09 47
Email: copyright@iso.org
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